

<b>Notice of References Cited</b>	Application/Control No. 09/295,935	Applicant(s)/Patent Under Reexamination STECYK ET AL.	
	Examiner Annan Q. Shang	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,025,869	02-2000	Stas et al.	725/28
	B	US-6,216,263	04-2001	Elam, Carl M.	725/28
	C	US-6,072,520	06-2000	Yuen et al.	725/27
	D	US-6,732,367	05-2004	Ellis et al.	725/27
	E	US-5,973,683	10-1999	Cragun et al.	715/719
	F	US-5,859,662	01-1999	Cragun et al.	725/137
	G	US-5,828,402	10-1998	Collings, Timothy David	725/28
	H	US-5,995,133	11-1999	Kim, Seong-Ouk	725/28
	I	US-2002/0109732	08-2002	Ward et al.	345/810
	J	US-2004/0128681	07-2004	Hancock et al.	725/030
	K	US-6,675,384	01-2004	Block et al.	725/28
	L	US-6,286,141	09-2001	Browne et al.	725/39
	M	US-6,144,401	11-2000	Casement et al.	725/30

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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